

| L Number | Hits | Search Text | DB | Time stamp |
|----------|------|---|--------------------------------|---------------------|
| 1 | 0 | scan adj2 test and flip adj flop and circuit and conversion adj circuit and output adj2 storage | USPAT; EPO; JPO; DERWENT | 2004/09/16 20:57 |
| 2 | 0 | scan adj2 test and flip adj flop and conversion adj circuit and output adj2 storage | USPAT; EPO; JPO; DERWENT | 2004/09/16 20:57 |
| 3 | 3 | scan adj2 test and flip adj flop and conversion adj circuit and output near5 storage | USPAT; EPO; JPO; DERWENT | 2004/09/16 20:57 |